

# PRODUCT/PROCESS CHANGE NOTIFICATION

PCN IPG-IPC/14/8713 Dated 02 Oct 2014

**HBIP40 Technology for Voltage reference TL1431** 

#### **Table 1. Change Implementation Schedule**

gg		
Forecasted implementation date for change	19-Dec-2014	
Forecasted availability date of samples for customer	25-Sep-2014	
Forecasted date for <b>STMicroelectronics</b> change Qualification Plan results availability	25-Sep-2014	
Estimated date of changed product first shipment	01-Jan-2015	

## **Table 2. Change Identification**

Product Identification (Product Family/Commercial Product)	see attached list	
Type of change	Product design change	
Reason for change	This manufacturing change will improve service to ST Customers	
Description of the change	Following Divisional Commitments towards a continuous improvement philosophy, a more fine geometry Bipolar Technology called HBIP40 has been qualified in ST. ST is going to use this improved technology to redesign the Voltage Reference TL1431. The present PCN notifies the fully qualification of TL1431AC and TL1431C devices. Quality and electrical performances are guaranteed	
Change Product Identification	Digit "H" is marked on the physical parts, on the string after P/N marking	
Manufacturing Location(s)		

Table 3. L	ist of	Attachme	ents
------------	--------	----------	------

Customer Part numbers list	
Qualification Plan results	

Customer Acknowledgement of Receipt	PCN IPG-IPC/14/8713
Please sign and return to STMicroelectronics Sales Office	Dated 02 Oct 2014
□ Qualification Plan Denied	Name:
□ Qualification Plan Approved	Title:
	Company:
□ Change Denied	Date:
□ Change Approved	Signature:
Remark	
ı	

**47/**.

## **DOCUMENT APPROVAL**

Name	Function
Riviera, Antonio	Marketing Manager
Naso, Lorenzo	Product Manager
Moretti, Paolo	Q.A. Manager

**A7**/.

#### WHAT:

Following Divisional Commitments towards a continuous improvement philosophy, a more fine geometry Bipolar Technology called HBIP40 has been qualified in ST. ST is going to use this improved technology to redesign the Voltage Reference TL1431. The present PCN notifies the fully qualification of TL1431AC and TL1431C devices. Quality and electrical performances are guaranteed.

For the complete list of the part numbers affected by the change, please refer to the attached Products list.

#### WHY:

New equipment utilization, capacity optimization.

This manufacturing change will improve service to ST Customers.

#### HOW:

The qualification program mainly consist of reliability tests and comparative electrical characterizations.

The related reliability report is annexed to this document.

The changes here reported do not affect the electrical, dimensional and thermal parameters of the products, keeping unchanged all information reported on the relevant datasheets.

#### WHEN:

Te implementation will be finalized within Week 50-14

#### Marking and traceability:

Digit "H" is marked on the physical parts, on the string after P/N marking.

The changed here reported will not affect the electrical, dimensional and thermal parameters keeping unchanged all information reported on the relevant datasheets.

There is as well no change in the packing process or in the standard delivery quantities.

Lack of acknowledgement of the PCN within 30 days will constitute acceptance of the change. After acknowledgement, lack of additional response within the 90 day period will constitute acceptance of the change (Jedec Standard No. 46-C).

In any case, first shipments may start earlier with customer's written agreement.





#### Linear Voltage Regulators & Vref Quality and Reliability

REL.6043-066W-13

## **Reliability Report**

#### Voltage References

**New Products** 

TL1431AC & TL1431C

Technology HBIP40V Package: SO8 & SOT23-3L

Camaral	Information
General	intormation

Product Line M43101

Product Description Programmable voltage

reference

P/N TL1431ACDT

Product Group TL1431ACL3T

IPC

**Product division** Linear Voltage Regulators

& Vref

Packages SO8 SOT23

Silicon Process technology HBIP40V

Locations

Wafer fab AMK6

Assembly plant SHENZHEN (SO8)

CARSEM (SOT23-3L)

Reliability Lab CATANIA

Reliability assessment Pass

#### **DOCUMENT INFORMATION**

Version	Date	Pages	Prepared by	Approved by	Comment
1.0	Jun-2013	8	Giuseppe Failla	Giovanni Presti	Final report

Note: This report is a summary of the reliability trials performed in good faith by STMicroelectronics in order to evaluate the potential reliability risks during the product life using a set of defined test methods.

This report does not imply for STMicroelectronics expressly or implicitly any contractual obligations other than as set forth in STMicroelectronics general terms and conditions of Sale. This report and its contents shall not be disclosed to a third party without previous written agreement from STMicroelectronics.



#### **Industrial Power Conversion**

REL.6043-066W-13

## Linear Voltage Regulators & Vref Quality and Reliability

## **TABLE OF CONTENTS**

1	APPL	LICABLE AND REFERENCE DOCUMENTS	3
		SSARY	
		ABILITY EVALUATION OVERVIEW	
	3.1	OBJECTIVES	3
		CONCLUSION	
4	DEVI	CE CHARACTERISTICS	4
	4.1	DEVICE DESCRIPTION	4
		CONSTRUCTION NOTE	
5	TEST	S RESULTS SUMMARY	5
	5.1	TEST VEHICLE	5
		TEST PLAN AND RESULTS SUMMARY	
6	ANNE	EXES	
	6.1	DEVICE DETAILS	6
	6.2	TESTS DESCRIPTION	8



#### **Industrial Power Conversion**

Linear Voltage Regulators & Vref Quality and Reliability REL.6043-066W-13

## 1 APPLICABLE AND REFERENCE DOCUMENTS

Document reference	Short description
JESD47	Stress-Test-Driven Qualification of Integrated Circuits
AECQ100	Failure mechanism based stress test qualification for integrated circuits

## **2 GLOSSARY**

DUT	Device Under Test
SS	Sample Size

## **3 RELIABILITY EVALUATION OVERVIEW**

## 3.1 Objectives

New products qualification: TL1431ACDT & TL1431ACL3T diffused in technology HBIP40 in SO8 and SOT23 packages.

## 3.2 Conclusion

The present reliability evaluation is considered positive with reference to the product versions "C" and "AC", having at datasheet operating temperature from -20°C to 70°C.



#### **Industrial Power Conversion**

#### Linear Voltage Regulators & Vref Quality and Reliability

REL.6043-066W-13

## **4 DEVICE CHARACTERISTICS**

## 4.1 Device description

The TL1431 is a programmable shunt voltage reference with guaranteed temperature stability over the entire operating temperature range. The output voltage may be set to any value between 2.5 V and 36 V with two external resistors.

The TL1431 operates with a wide current range from 1 to 100 mA with a typical dynamic impedance of 0.2 Ω.

#### 4.2 Construction note

P/N	TL1431ACDT	TL1431ACL3T	
	SO8	SOT23-3L	
Wafer/Die fab. information			
Wafer fab manufacturing location	SINGAPORE	Ang Mo Kio	
Technology	HBIF	P40V	
Die finishing back side	Lapped	Silicon	
Die size	830, 780	) micron	
Passivation type	PVAPOX/	NITRIDE	
Wafer Testing (EWS) information			
Electrical testing manufacturing			
location	Ang Mo	Kio EWS	
Tester	ASL1000		
Test program	M431_AFTER_ESI.nx4		
Assembly information			
Assembly site	SHENZHEN B/E	CARSEM M	
Package description	SO 08 .15 JEDEC	SOT 23 3 LDS	
Molding compound	Ероху	epoxy	
Frame material	NiThPdAgAu	HDLF NiPdAu	
Die attach material	Ероху Ероху		
Wires bonding materials/diameters	1 mils CU Wire		
Final testing information			
Testing location	SHENZHEN B/E CARSEM S		
Tester	ASL1000		
Test program	M431_STS_01.nx4 M431_1		



#### Linear Voltage Regulators & Vref Quality and Reliability

REL.6043-066W-13

## **5 TESTS RESULTS SUMMARY**

## 5.1 Test vehicle

Lot #	Process/ Package	Product Line	Comments
1	SO8	M43101	
2	SOT23-3L (grade 3)	M43101	

## 5.2 Test plan and results summary

P/N TL1431ACDT\_ TL1431ACL3T

Test	РС	Std ref.	Conditions	Steps	Failure/SS		Note	
					Steps	SO8	SOT23-3L	
Die Or	ient	ed Tests						
HTOL		JESD22 A-108	Ta = 85°C, BIAS +5V		168 H	0/77	0/77	
	Ν				500 H	0/77	0/77	
					1000 H	0/77	0/77	
		JESD22 A-103	Ta = 150°C		168 H	0/45	0/45	
HTSL	Ν				500 H	0/45	0/45	
					1000 H	0/45	0/45	
Package Oriented Tests								
PC		JESD22 A-113	Drying 24 H @ 125°C Store 168 H @ Ta=85°C Rh=85% Oven Reflow @ Tpeak=260°C 3 times		Final	Pass	Pass	
AC	Υ	JESD22 A-102	Pa=2Atm / Ta=121°C		96 H	0/77	0/77	
TC		JESD22 A-104	Ta = -40°C to 125°C		100 cy	0/77	0/77	
	Υ				200 cy	0/77	0/77	
					500 cy	0/77	0/77	
THB		JESD22 A-101	Ta = 85°C, RH=85%, BIAS +2.8V		168 H	0/77	0/77	
	Υ				500 H	0/77	0/77	
					1000 H	0/77	0/77	
Other 7	Γest	s						
		AEC	HBM	3	2KV	Pass		
ESD	N	Q101-001, 002 and	CDM	3	1.5KV	Pass		
		002 and 005	MM	3	200V	Pass		

Product grade 3



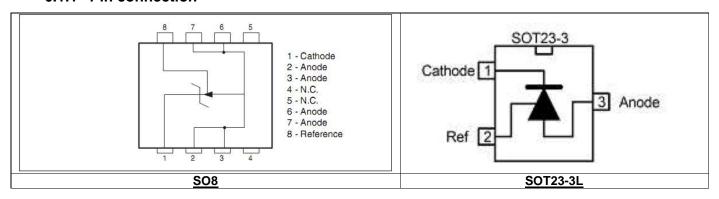
#### Linear Voltage Regulators & Vref Quality and Reliability

REL.6043-066W-13

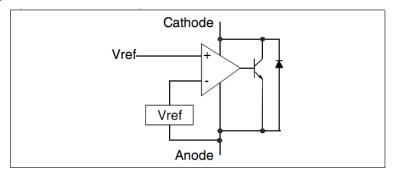
## **6 ANNEXES**

## 6.1 Device details

#### 6.1.1 Pin connection



#### 6.1.2 Block diagram



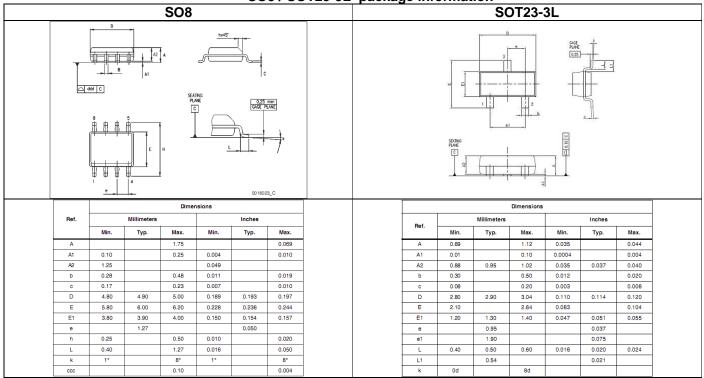


REL.6043-066W-13

#### Linear Voltage Regulators & Vref Quality and Reliability

## 6.1.3 Package outline/Mechanical data

SO8 / SOT23-3L package information





#### **Industrial Power Conversion**

REL.6043-066W-13

## Linear Voltage Regulators & Vref Quality and Reliability

## 6.2 Tests Description

Test name	Description	Purpose						
Die Oriented								
HTOL High Temperature Operative Life	The device is stressed in static or dynamic configuration, approaching the operative max. absolute ratings in terms of junction temperature and bias condition.	To determine the effects of bias conditions and temperature on solid state devices over time. It simulates the devices' operating condition in an accelerated way.  The typical failure modes are related to, silicon degradation, wire-bonds degradation, oxide faults.						
HTSL High Temperature Storage Life		To investigate the failure mechanisms activated by high temperature, typically wire-bonds solder joint ageing, data retention faults, metal stress- voiding.						
Package Oriented								
<b>PC</b> Preconditioning	The device is submitted to a typical temperature profile used for surface mounting devices, after a controlled moisture absorption.	As stand-alone test: to investigate the moisture sensitivity level.  As preconditioning before other reliability tests: to verify that the surface mounting stress does not impact on the subsequent reliability performance.  The typical failure modes are "pop corn" effect and delamination.						
AC	The device is stored in saturated steam, at							
Auto Clave	fixed and controlled conditions of pressure	die or package materials, related to chemical						
(Pressure Pot)  TC  Temperature  Cycling	The device is submitted to cycled temperature excursions, between a hot and a cold chamber in air atmosphere.	contamination and package hermeticity.  To investigate failure modes related to the thermo-mechanical stress induced by the different thermal expansion of the materials interacting in the die-package system. Typical failure modes are linked to metal displacement, dielectric cracking, molding compound delamination, wire-bonds failure, die-attach layer degradation.						
<b>THB</b> Temperature Humidity Bias	The device is biased in static configuration minimizing its internal power dissipation, and stored at controlled conditions of ambient temperature and relative humidity.	To evaluate the package moisture resistance with electrical field applied, both electrolytic and galvanic corrosion are put in evidence.						
Other Test								
<b>ESD</b> Electro Static Discharge	The device is submitted to a high voltage peak on all his pins simulating ESD stress according to different simulation models.  CDM: Charged Device Model  HBM: Human Body Model  MM: Machine Model	To classify the device according to his susceptibility to damage or degradation by exposure to electrostatic discharge.						

#### Please Read Carefully:

Information in this document is provided solely in connection with ST products. STMicroelectronics NV and its subsidiaries("ST") reserve the right to make changes, corrections, modifications or improvements, to this document, and the products and services described herein at any time, without notice.

All ST products are sold pursuant to ST's terms and conditions of sale.

Purchasers are solely responsible for the choice, selection and use of the ST products and services described herein, and ST assumes no liability whatsoever relating to the choice, selection or use of the ST products and services described herein.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted under this document. If any part of this document refers to any third party products or services it shall not be deemed a license grant by ST for the use of such third party products or services, or any intellectual property contained therein or considered as a warranty covering the use in any manner whatsoever of such third party products or services or any intellectual property contained therein.

UNLESS OTHERWISE SET FORTH IN ST'S TERMS AND CONDITIONS OF SALE ST DISCLAIMS ANY EXPRESS OR IMPLIED WARRANTY WITH RESPECT TO THE USE AND/OR SALE OF ST PRODUCTS INCLUDING WITHOUT LIMITATION IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION), OR INFRINGEMENT OF ANY PATENT, COPYRIGHT OR OTHER INTELLECTUAL PROPERTY RIGHT.

ST PRODUCTS ARE NOT DESIGNED OR AUTHORIZED FOR USE IN: (A) SAFETY CRITICAL APPLICATIONS SUCH AS LIFE SUPPORTING, ACTIVE IMPLANTED DEVICES OR SYSTEMS WITH PRODUCT FUNCTIONAL SAFETY REQUIREMENTS; (B) AERONAUTIC APPLICATIONS; (C) AUTOMOTIVE APPLICATIONS OR ENVIRONMENTS, AND/OR (D) AEROSPACE APPLICATIONS OR ENVIRONMENTS. WHERE ST PRODUCTS ARE NOT DESIGNED FOR SUCH USE, THE PURCHASER SHALL USE PRODUCTS AT PURCHASER'S SOLE RISK, EVEN IF ST HAS BEEN INFORMED IN WRITING OF SUCH USAGE, UNLESS A PRODUCT IS EXPRESSLY DESIGNATED BY ST AS BEING INTENDED FOR "AUTOMOTIVE, AUTOMOTIVE SAFETY OR MEDICAL" INDUSTRY DOMAINS ACCORDING TO ST PRODUCT DESIGN SPECIFICATIONS. PRODUCTS FORMALLY ESCC, QML OR JAN QUALIFIED ARE DEEMED SUITABLE FOR USE IN AEROSPACE BY THE CORRESPONDING GOVERNMENTAL AGENCY.

#### **RESTRICTIONS OF USE AND CONFIDENTIALITY OBLIGATIONS:**

THIS DOCUMENT AND ITS ANNEXES CONTAIN ST PROPRIETARY AND CONFIDENTIAL INFORMATION. THE DISCLOSURE, DISTRIBUTION, PUBLICATION OF WHATSOEVER NATURE OR USE FOR ANY OTHER PURPOSE THAN PROVIDED IN THIS DOCUMENT OF ANY INFORMATION CONTAINED IN THIS DOCUMENT AND ITS ANNEXES IS SUBMITTED TO ST PRIOR EXPRESS AUTHORIZATION. ANY UNAUTHORIZED REVIEW, USE, DISCLOSURE OR DISTRIBUTION OF SUCH INFORMATION IS EXPRESSLY PROHIBITED.

Resale of ST products with provisions different from the statements and/or technical features set forth in this document shall immediately void any warranty granted by ST for the ST product or service described herein and shall not create or extend in any manner whatsoever, any liability of ST.

ST and the ST logo are trademarks or registered trademarks of ST in various countries.

Information in this document supersedes and replaces all information previously supplied.

The ST logo is a registered trademark of STMicroelectronics. All other names are the property of their respective owners

© 2014 STMicroelectronics - All rights reserved.

STMicroelectronics group of companies

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan - Malaysia - Malta - Morocco - Philippines - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America

www.st.com

